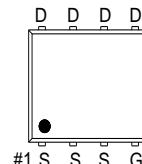
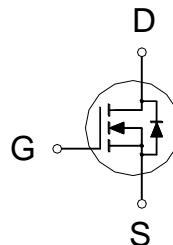


NIKO-SEM
**N-Channel Enhancement Mode
Field Effect Transistor**
**PE636BA
PDFN 3x3P
Halogen-Free & Lead-Free**
**PRODUCT SUMMARY**

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
30V	9mΩ	33A


G : GATE
D : DRAIN
S : SOURCE
ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Drain-Source Voltage	V_{DS}	30	V
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current ³	I_D	33	A
		21	
		10	
		8	
Pulsed Drain Current ¹	I_{DM}	100	
Avalanche Current	I_{AS}	20	
Avalanche Energy	E_{AS}	20	mJ
Power Dissipation	P_D	17.8	W
		7	
		1.7	
		1	
Operating Junction & Storage Temperature Range	T_j, T_{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient ²	$R_{\theta JA}$	75	7	°C / W
Junction-to-Case	$R_{\theta JC}$			

¹Pulse width limited by maximum junction temperature.²The value of $R_{\theta JA}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A = 25^\circ\text{C}$.³Package limitation current is 13A**ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$	30			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	1.3	1.8	2.3	

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Gate-Body Leakage	I_{GSS}	$V_{DS} = 0V, V_{GS} = \pm 20V$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 24V, V_{GS} = 0V$			1	μA
		$V_{DS} = 20V, V_{GS} = 0V, T_J = 55^{\circ}C$			10	
Drain-Source On-State Resistance ¹	$R_{DS(ON)}$	$V_{GS} = 4.5V, I_D = 10A$		9.9	12	$m\Omega$
		$V_{GS} = 10V, I_D = 10A$		7.4	9	
Forward Transconductance ¹	g_{fs}	$V_{DS} = 10V, I_D = 10A$		34		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = 15V, f = 1MHz$		774		pF
Output Capacitance	C_{oss}			139		
Reverse Transfer Capacitance	C_{rss}			81		
Gate Resistance	R_g	$V_{GS} = 0V, V_{DS} = 0V, f = 1MHz$		3.1		Ω
Total Gate Charge ²	$Q_{g(VGS=10V)}$	$V_{DS} = 15V, I_D = 10A$		15.5		nC
	$Q_{g(VGS=4.5V)}$			8.3		
Gate-Source Charge ²	Q_{gs}			2.2		
Gate-Drain Charge ²	Q_{gd}			4.4		
Turn-On Delay Time ²	$t_{d(on)}$	$V_{DD} = 15V$ $I_D \approx 10A, V_{GEN} = 10V, R_G = 6\Omega$		23		nS
Rise Time ²	t_r			20		
Turn-Off Delay Time ²	$t_{d(off)}$			40		
Fall Time ²	t_f			20		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^{\circ}C$)						
Continuous Current ³	I_S				14.8	A
Forward Voltage ¹	V_{SD}	$I_F = 10A, V_{GS} = 0V$			1.2	V
Reverse Recovery Time	t_{rr}	$I_F = 10A, dI_F/dt = 100A/\mu S$		9.5		nS
Reverse Recovery Charge	Q_{rr}			1.4		nC

¹Pulse test : Pulse Width $\leq 300\ \mu sec$, Duty Cycle $\leq 2\%$.

²Independent of operating temperature.

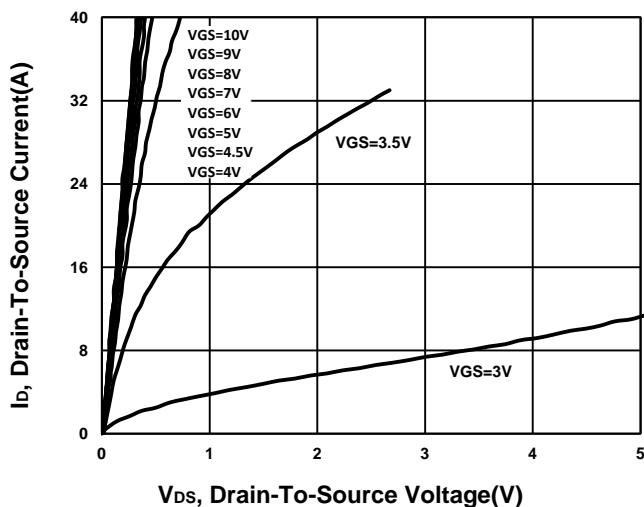
³Package limitation current is 13A

NIKO-SEM

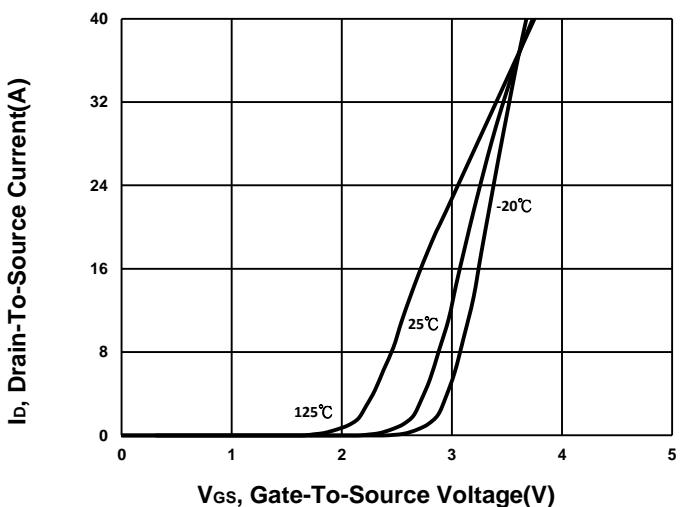
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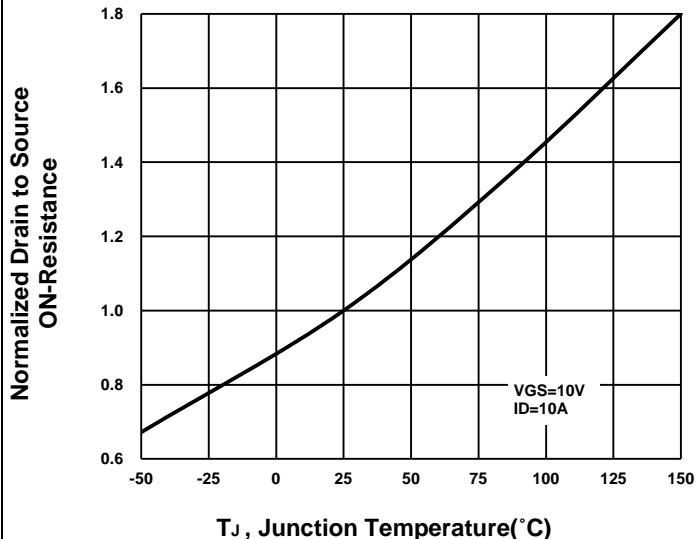
Output Characteristics



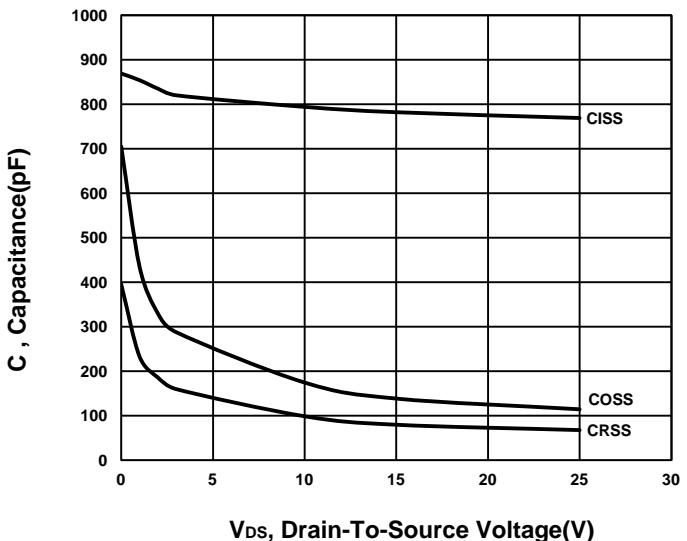
Transfer Characteristics



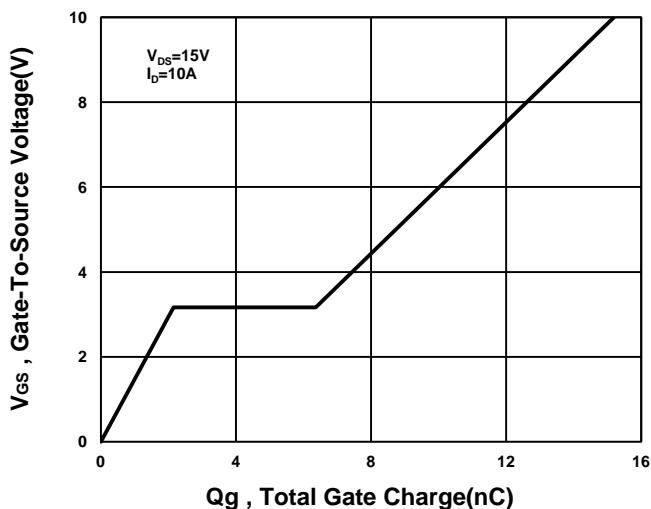
On-Resistance VS Temperature



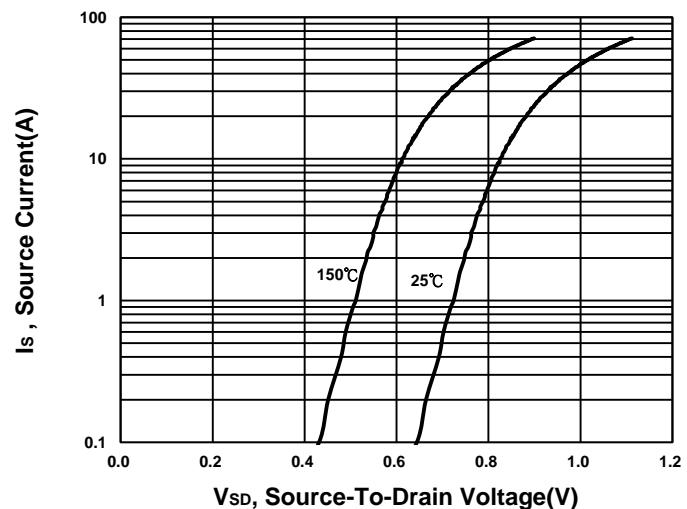
Capacitance Characteristic



Gate charge Characteristics



Source-Drain Diode Forward Voltage



NIKO-SEM

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